


<b>Search Notes</b>  	<b>Application/Control No.</b>  10530004	<b>Applicant(s)/Patent Under Reexamination</b>  VAANANEN, JOHANNES
	<b>Examiner</b>  Takele, Meseker	<b>Art Unit</b>  2175

SEARCHED			
Class	Subclass	Date	Examiner
715	764, 778, 859, 856, 864, 865, 781, 784, 788, 800, 801,	3/27/2010	MT
345	158, 419	3/27/2010	MT

SEARCH NOTES		
Search Notes	Date	Examiner
East earch (US -PGPUB, ASPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM-TDBS)	3/27/2010	MT
Inventor search	3/27/2010	MT
Consult with Primary Sy Luu	06/09/2007	MT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--